## Application/Control No. Applicant(s)/Patent Under Reexamination 10/523,854 LEE ET AL. **Notice of References Cited** Examiner Art Unit Page 1 of 1 1655 Randall Winston **U.S. PATENT DOCUMENTS** Date **Document Number** Classification Name Country Code-Number-Kind Code MM-YYYY 424/735 02-2002 US-2002/0025348 Basu et al. Α US-В US-С US-D US-Ε US-F US-G USн

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